

X-RAY PHOTOELECTRON SPECTROSCOPY (XPS)

MANUFACTURER : VG Scientific

MODEL : Escalab MkII

Analysis

- Multisegment apparatus equipped with an ultra-high vacuum system
- Surface analysis coupling 4 characterization techniques: X-ray Photoelectron Spectroscopy (XPS); Secondary Ion Mass Spectrometry (SIMS), Ion Scattering Spectroscopy (ISS); Auger Scanning Microscopy (ASM)

Characteristics

- Double Source Mg-Al; large radius hemispherical analyzer; Monochannel detection
- Resolution is 0.88 eV on Silver
- Integrated high temperature and high pressure reactor

MODES

SIMS

- Manufacturer : SIMSLAB
- Model : MM12-12S
- Large quadrupole based scanning SIMS-Ar and SIMS-Ga
- Mass resolution : 1 amu (over a range of 1 amu to 800 amu)
- Spatial resolution : 100 μm (Ar^+) and 1 μm (Ga^+)

ISS

- Model : VG ISS
- Resolution : 1% with He 1000 eV (Au)

ASM

- Model : MicroLab500
- Canon LEG 500 of 30 keV
- Spatial resolution : 1 μm